

**Search Notes**

Application/Control No.

10/718,192

Examiner

Chris C. Chu

Applicant(s)/Patent under  
Reexamination

KUO ET AL.

Art Unit

2815

**SEARCHED**

Class	Subclass	Date	Examiner
257	E23.119, 738, 704, 706 & 720	3/13/2006	C.C.
257	E23.087	3/13/2006	C.C.
257	E23.101	3/13/2006	C.C.

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; and IBM_TDB;	3/13/2006	C.C.